

IEEE SW Test Workshop

Semiconductor Wafer Test Workshop

June 8 - 11, 2014 | San Diego, California

Extend the lifetime of your current Probe Card Analyzer

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Agenda

- Prv and VX machine upgrade path
 - Including mechanical, optical and electrical **Upgrades**
 - Microscope upgrades
 - Obsolete part replacement
- Correlation results
- PMM Upgrade options

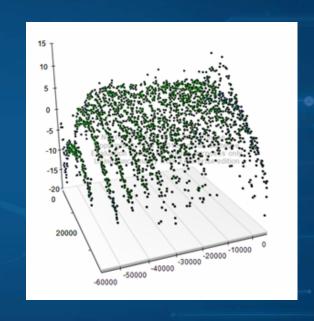


VX upgrade

- New win 7 computer
- Ethernet capability

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- Reference files Compatibility
- VX Channel motherboard compatible
- Vision recipe for all probe-tip types
- 3D display of Probe Card image



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Upgrade details

- Chuck refurbishment
- Dot rework / refurbishing
- Optional dot sizes possible
- Lens rework
- Camera replacements with Ethernet BW/ type
- Light source upgraded to single-phase light
- New motors and driver boards
- Automated counter-weight balance manipulator



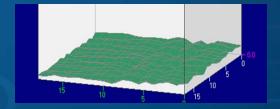
Upgrade details – cont'd

- XY stage remapped
- Z stage rebuilt with 50kg stage (minimum)
- Microscope
 - Refurbished including new light source
 - Motorized microscope optional
- Gram force post refurbished



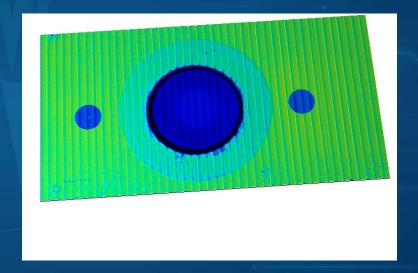


XY stage can be expanded to 8"x 8" travel



Upgrade details – optically confirmed

- Single-phase blue light chuck a photo in process
- 3D Verification of chuck and profiler





Electrical Upgrades

- Channel layout is compatible with original
- Same PMM
 - New PMM/ASB flexible channels and relay location are optional
- Standard Upgrade Includes
 - Cable-management system
 - System electronics upgraded
 - New power supplies
 - New Cooling fans
 - Diagnostic probe upgraded
 - Refurbished pogo block
 - New electrical switches
- Optional upgrade capabilities
 - Additional channels with new PMM (up to 10,000)
 - Add-on Advance Smart block flexible relay positions
 - Capable of Direct dock probe card test



Electrical upgrade – cont'd

New USB IO, etc.







New PMM OS tester with scramble board



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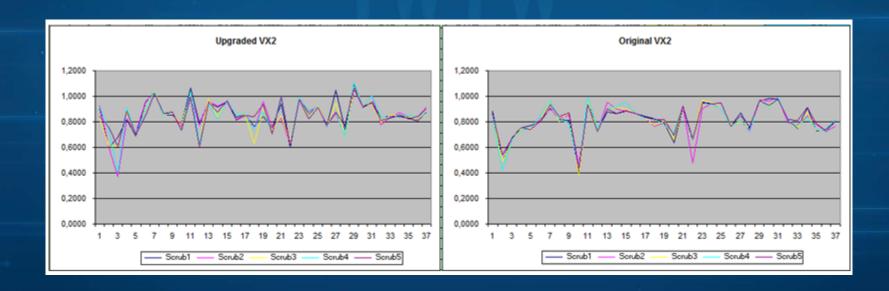






Correlation results

 Same results on an upgraded VX machine vs. original VX machine



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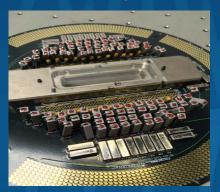
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Correlation results cont'd



PMM Upgrade Option

Design your probecard with respect to the tester capabilities





Don't settle for your analyzer's capability limits Ask how we can help with our new PMM





Thanks for your attention

Please contact us with any questions

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